

DESCRIPTION

The M74LS290P is a semiconductor integrated circuit containing an asynchronous decade counter function with direct reset and direct 9-set inputs.

FEATURES

- Direct reset inputs provided
- Direct 9-set inputs provided
- Usable independently as binary and divide-by-5 counter
- High-speed counting ($f_{max} = 75MHz$ typical)
- Wide operating temperature range ($T_a = -20\sim+75^\circ C$)

APPLICATION

General purpose, for use in industrial and consumer equipment.

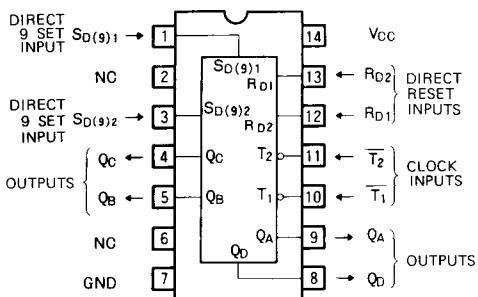
FUNCTIONAL DESCRIPTION

This device is composed of independent binary and divide-by-5 counters. Clock input \bar{T}_1 and output Q_A are employed for use as a binary counter while clock input \bar{T}_2 and Q_B , Q_C and Q_D are employed for use as a divide-by-5 counter. When employed as a decade counter, Q_A and \bar{T}_2 are connected and by making \bar{T}_1 the input, the BCD code output appears in outputs Q_A , Q_B , Q_C and Q_D . Counting is performed when \bar{T}_1 and \bar{T}_2 are changed from high to low.

The binary and divide-by-5 counters can be reset or set to 9 simultaneously by setting direct reset inputs R_{D1} and R_{D2} and direct 9 set inputs $SD(9)1$ and $SD(9)2$ high. For use as a counter, either R_{D1} or R_{D2} , or both, and $SD(9)1$ or $SD(9)2$, or both, are set low.

Also provided is the M74LS90P with the same functions and electrical characteristics. This device differs only in its pin configuration.

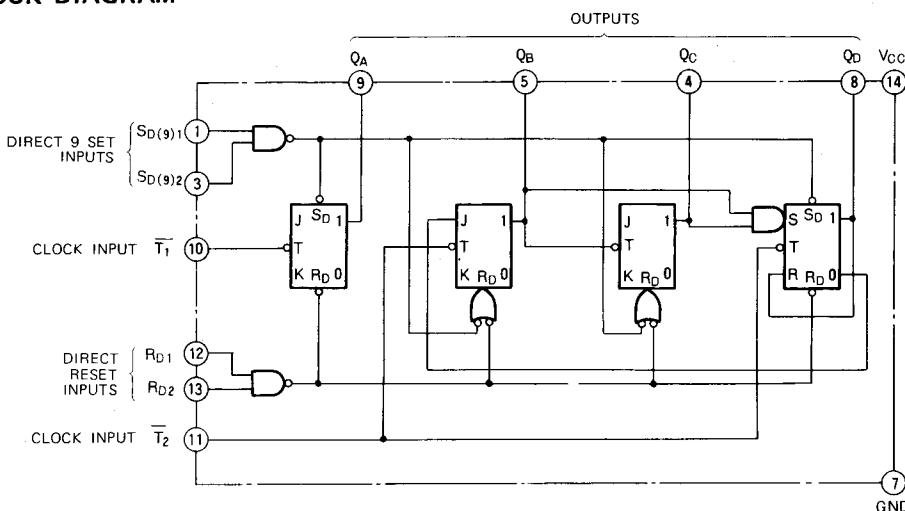
PIN CONFIGURATION (TOP VIEW)



Outline 14P4

NC : NO CONNECTION

BLOCK DIAGRAM



FUNCTION TABLE (Note 1)

\bar{T}	R _{D1}	R _{D2}	S _{D(9)1}	S _{D(9)2}	Q _A	Q _B	Q _C	Q _D
X	H	H	L	X	L	L	L	L
X	H	H	X	L	L	L	L	L
X	X	X	H	H	H	L	L	H
↓	L	X	L	X	Count			
↓	X	L	X	L	Count			
↓	L	X	X	L	Count			
↓	X	L	L	X	Count			

Note 1: ↓ : Transition from high to low

X : Irrelevant

Count number	Q _A	Q _B	Q _C	Q _D
0	L	L	L	L
1	H	L	L	L
2	L	H	L	L
3	H	H	L	L
4	L	L	H	L
5	H	L	H	L
6	L	H	H	L
7	H	H	H	L
8	L	L	L	H
9	H	L	L	H

(1) Valid when Q_A and \bar{T}_2 are connected and \bar{T}_1 is made the input

ABSOLUTE MAXIMUM RATINGS ($T_a = -20 \sim +75^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions			Limits	Unit
		Min	Typ	Max		
V _{CC}	Supply voltage				-0.5 ~ +7	V
V _I	Input voltage	Inputs \bar{T}_1 , \bar{T}_2			-0.5 ~ +5.5	V
		Inputs R _{D1} , R _{D2} , S _{D(9)1} , S _{D(9)2}			-0.5 ~ +15	
V _O	Output voltage	High-level state			-0.5 ~ V _{CC}	V
T _{opr}	Operating free-air ambient temperature range				-20 ~ +75	°C
T _{stg}	Storage temperature range				-65 ~ +150	°C

RECOMMENDED OPERATING CONDITIONS ($T_a = -20 \sim +75^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Limits			Unit
		Min	Typ	Max	
V _{CC}	Supply voltage	4.75	5	5.25	V
I _{OH}	High-level output current	V _{OH} ≥ 2.7V	0	-400	μA
I _{OL}	Low-level output current	V _{OL} ≤ 0.4V	0	4	mA
		V _{OL} ≤ 0.5V	0	8	mA

ELECTRICAL CHARACTERISTICS ($T_a = -20 \sim +75^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Test conditions			Limits		Unit
		Min	Typ	Max	Min	Typ	
V _{IH}	High-level input voltage				2		V
V _{IL}	Low-level input voltage					0.8	V
V _{IC}	Input clamp voltage	V _{CC} = 4.75V, I _{IC} = -18mA				-1.5	V
V _{OH}	High-level output voltage	V _{CC} = 4.75V, V _I = 0.8V V _I = 2V, I _{OH} = -400 μA			2.7	3.4	V
V _{OL}	Low-level output voltage	V _{CC} = 4.75V	I _{OL} = 4 mA (Note 2)		0.25	0.4	V
		V _I = 0.8V, V _I = 2V	I _{OL} = 8 mA (Note 2)		0.35	0.5	V
I _{IH}	High-level input current	R _{D1} , R _{D2} , S _{D(9)1} , S _{D(9)2}	V _{CC} = 5.25V, V _I = 2.7V			20	μA
		\bar{T}_1		40			
		\bar{T}_2		80			
		\bar{T}_1	V _{CC} = 5.25V, V _I = 5.5V			0.2	mA
		\bar{T}_2	V _{CC} = 5.25V, V _I = 10V			0.4	
I _{IL}	Low-level input current	R _{D1} , R _{D2} , S _{D(9)1} , S _{D(9)2}	V _{CC} = 5.25V, V _I = 0.4V			0.1	mA
		\bar{T}_1				-0.4	
		\bar{T}_2				-2.4	
I _{OS}	Short-circuit output current (Note 3)		V _{CC} = 5.25V, V _O = 0 V			-3.2	mA
			V _{CC} = 5.25V (Note 4)			-100	
I _{CC}	Supply current				9	15	mA

* : All typical values are at $V_{CC} = 5\text{ V}$, $T_a = 25^\circ\text{C}$.

Note 2: Output Q_A should be tested with input \bar{T}_2 connected to output Q_A.

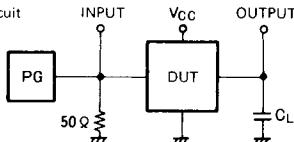
Note 3: All measurements should be done quickly and not more than one output should be shorted at a time.

Note 4: I_{CC} is measured with \bar{T}_1 , \bar{T}_2 , S_{D(9)1} and S_{D(9)2} at 0V after R_{D1} and R_{D2} have been set to 0V after 4.5V.

DECade Counter**SWITCHING CHARACTERISTICS** ($V_{CC} = 5\text{ V}$, $T_a = 25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
f_{max}	Maximum clock frequency, from input \bar{T}_1 to output Q_A		32	75		MHz
f_{max}	Maximum clock frequency, from input \bar{T}_2 to output Q_B		16	30		MHz
t_{PLH}	Low-to-high-level, high-to-low-level output propagation time, from input \bar{T}_1 to output Q_A			7	16	ns
t_{PHL}	Low-to-high-level, high-to-low-level output propagation time, from input \bar{T}_2 to output Q_B			8	18	ns
t_{PLH}	Low-to-high-level, high-to-low-level output propagation time, from input \bar{T}_2 to output Q_B			15	48	ns
t_{PHL}	Low-to-high-level, high-to-low-level output propagation time, from input \bar{T}_1 to output Q_C			16	50	ns
t_{PLH}	Low-to-high-level, high-to-low-level output propagation time, from input \bar{T}_2 to output Q_D			7	16	ns
t_{PHL}	Low-to-high-level, high-to-low-level output propagation time, from input \bar{T}_1 to output Q_D			8	21	ns
t_{PLH}	Low-to-high-level, high-to-low-level output propagation time, from inputs $S_{D(9)1}, S_{D(9)2}$ to outputs Q_A, Q_D			15	32	ns
t_{PLH}	High-to-low-level output propagation time, from inputs $S_{D(9)1}, S_{D(9)2}$ to outputs Q_B, Q_C			15	35	ns
t_{PHL}	High-to-low-level output propagation time, from inputs R_{D1}, R_{D2} to outputs Q_A, Q_B, Q_C, Q_D			7	32	ns
t_{PHL}	High-to-low-level output propagation time, from inputs R_{D1}, R_{D2} to outputs Q_A, Q_B, Q_C, Q_D			8	35	ns
				17	40	ns
				10	30	ns
				14	40	ns

Note 5: Measurement circuit

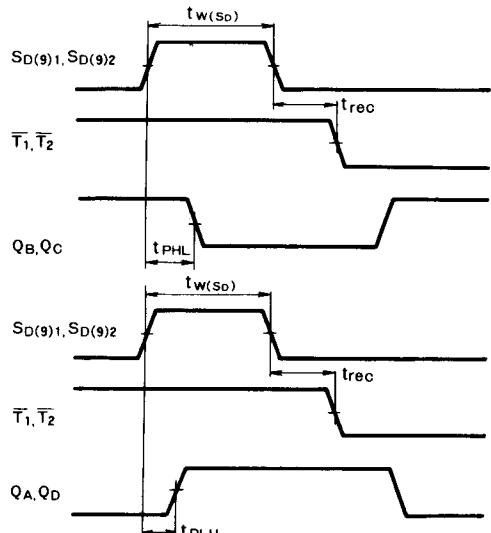
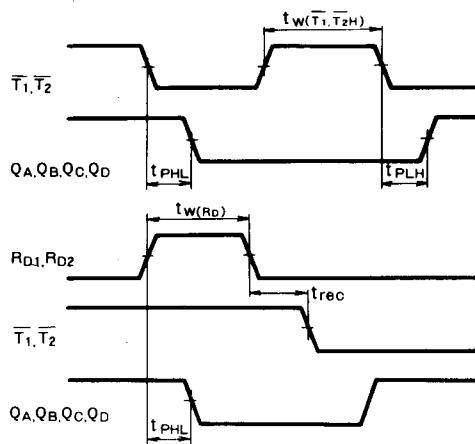


- (1) The pulse generator (PG) has the following characteristics:
 $PRR = 1\text{MHz}$, $t_r = 6\text{ns}$, $t_f = 6\text{ns}$, $t_w = 500\text{ns}$,
 $V_p = 3V_{pp}$, $Z_0 = 50\Omega$.

- (2) C_L includes probe and jig capacitance

TIMING REQUIREMENTS ($V_{CC} = 5\text{ V}$, $T_a = 25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
$t_w(\bar{T}_{1H})$	Clock input \bar{T}_1 high pulse width		15	6		ns
$t_w(\bar{T}_{2H})$	Clock input \bar{T}_2 high pulse width		30	17		ns
$t_w(R_0)$	Direct reset R_{D1}, R_{D2} pulse width		15	5		ns
$t_w(S_0)$	Direct 9 set $S_{D(9)1}, S_{D(9)2}$ pulse width		15	5		ns
t_r	Clock pulse rise time			500	100	ns
t_f	Clock pulse fall time			200	100	ns
$t_{rec}(R_0)$	Recovery time R_{D1}, R_{D2} to \bar{T}_1, \bar{T}_2		25	8		ns
$t_{rec}(S_0)$	Recovery time $S_{D(9)1}, S_{D(9)2}$ to \bar{T}_1, \bar{T}_2		25	8		ns

TIMING DIAGRAM (Reference level = 1.3V)

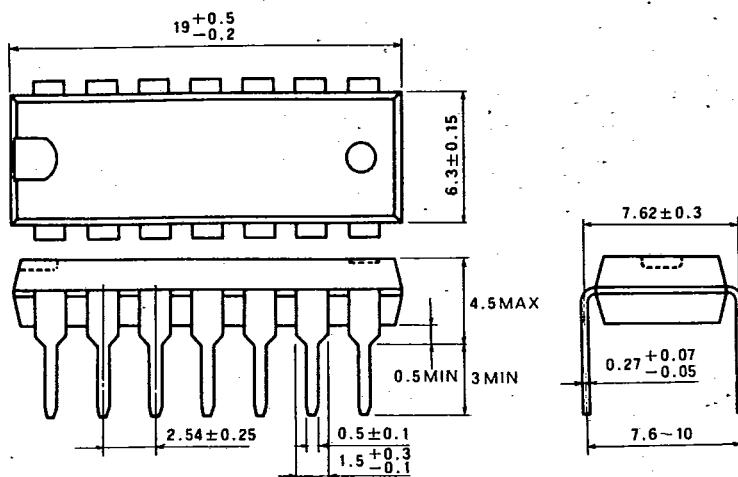
MITSUBISHI LSTTLs
PACKAGE OUTLINES

MITSUBISHI {DGTL LOGIC} 07E D 6249827 0013561 3

T-90-20

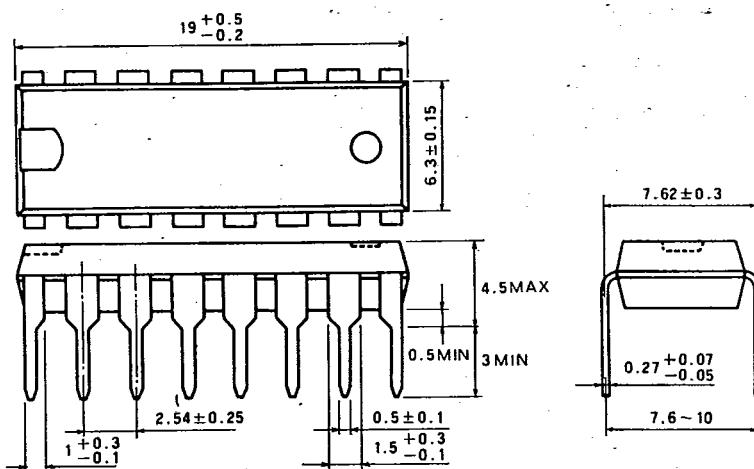
TYPE 14P4 14-PIN MOLDED PLASTIC DIL

Dimension in mm



TYPE 16P4 16-PIN MOLDED PLASTIC DIL

Dimension in mm



TYPE 20P4 20-PIN MOLDED PLASTIC DIL

Dimension in mm

